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## Online Materials

Online Supplements to Chapters

Supplement to Chapter 3: Linking ERPs with Neural and Cognitive Processes

Supplement to Chapter 4: Examples of the Design of ERP Experiments

Supplement to Chapter 5: Electrodes and Skin Potentials

Supplement to Chapter 6: A Closer Look at ICA-Based Artifact Correction

Supplement to Chapter 7: Real and Imaginary Components

Supplement to Chapter 8: A Closer Look at the Number of Trials

Supplement to Chapter 9: Comparing Conditions with Different Numbers of Trials or Different Levels of Noise

Supplement to Chapter 10: Normalizing Scalp Distributions

### **Online Files**

Fake data for testing online filters

### **Online Chapters**

Chapter 11: A Closer Look at Averaging: Convolution, Latency Variability, and Overlap

Chapter 12: Time and Frequency: A Closer Look at Filtering and Time–Frequency Analysis

Chapter 13: The Mass Univariate Approach and Permutation Statistics

Chapter 14: ERP Localization

Chapter 15: Reading, Writing, and Reviewing ERP Papers

Chapter 16: Setting Up and Running an ERP Lab